E4982A LCR Meter

1 MHz to 300 MHz/500 MHz/1 GHz/3 GHz





DATA SHEET

Specification (spec.)

Warranted performance. All specifications apply at 23 °C \pm 5 °C unless otherwise stated, and 30 minutes after the instrument has been turned on. Specifications include guard bands to account for the expected statistical performance distribution, measurement uncertainties, and changes in performance due to environmental conditions.

Following supplemental information is intended to provide information that is helpful for using the instrument.

Typical (typ.)

Expected performance of an average unit which does not include guardbands. It is not covered by the product warranty.

Supplemental performance data (SPD)

Represents the value of a parameter that is most likely to occur; the expected mean or average. It is not covered by the product warranty.

General characteristics or nominal (nom.)

A general, descriptive term that does not imply a level of performance. It is not covered by the product warranty.

Basic Measurement Characteristic

Measurement parameters	
Impedance parameters	Z , Y , Ls, Lp, Cs, Cp, Rs, Rp, X, G, B, D, Q, θ z [°], θ z [rad], θ y [°], θ y [rad], User defined parameter (A maximum of four parameters can be displayed at one time.)
Measurement range	
Impedance parameters	140 mΩ to 4.8 kΩ (Frequency = 1 MHz, Averaging factor = 8, Measurement time mode = 3, Oscillator level = 1 dBm, Measurement uncertainty $\leq \pm$ 10%, Calibration is performed within 23 °C \pm 5 °C, Measurement is performed within \pm 5 °C from the calibration temperature)

Source Characteristics

Frequency	
Range	1 MHz to 300 MHz (Option 030)
	1 MHz to 500 MHz (Option 050)
	1 MHz to 1 GHz (Option 100)
	1 MHz to 3 GHz (Option 300)
Resolution	1 kHz ¹
Uncertainty	_± 10 ppm (23 °C ± 5 °C)
	± 20 ppm (5 °C to 40 °C)
Oscillator level	
Cable length = 1 m	
Power range (When 50 Ω LOAD is connected to test port)	–40 dBm to 1 dBm
Current range (When SHORT is connected to test port)	0.0894 mArms to 10 mArms
Voltage range (When OPEN is connected to test port)	4.47 mVrms to 502 mVrms
Uncertainty (When 50 Ω LOAD is	(23 °C ± 5 °C)
connected to test port)	± 2 dB (frequency ≤ 1 GHz)
	± 3 dB (frequency > 1 GHz)
	(5 °C to 40 °C)
	± 4 dB (frequency ≤ 1 GHz)
	± 5 dB (frequency > 1 GHz)
Resolution	0.1 dB (When the unit is set at mV or mA, the entered value is rounded to 0.1 dB resolution.)
Cable length = 2 m (When option 0	02 is used)
Power range	Subtract the following attenuation from the power (setting value) at 1 m cable length:
	Attenuation [dB] = $0.42 \sqrt{f}$ (f: Frequency [GHz])
Uncertainty (When 50 Ω LOAD is	(23 °C ± 5 °C)
connected to test port)	± 3 dB (frequency ≤ 1 GHz)
	± 4 dB (frequency > 1 GHz)
	(5 °C to 40 °C)
	± 5 dB (frequency ≤ 1 GHz)
	± 6 dB (frequency > 1 GHz)
Resolution	0.1 dB (When the unit is set at mV or mA, the entered value is rounded to 0.1 dB resolution.)

Output impedance

50 Ω (nominal)

1. Applies to the units with firmware revision B.02.20 or later. (For the units with firmware revision below B.02.20, the resolution is 100 kHz.)

Measurement Accuracy

Condition for definition of accuracy:

- 23 °C ± 5 °C

- 7-mm connector of 3.5-mm-7-mm adapter connected to 3.5-mm terminal of test heads

Basic measurement uncertainty (Typical)

0.45 %

Measurement uncertainty

When OPEN/SHORT/LOAD calibration is performed:

Z, Y	$\pm (E_a + E_b) [\%]$
Δθ	$\pm \frac{\left(E_{a} + E_{b}\right)}{100} [rad]$
L, C, X, B	$\pm \left(E_{a} + E_{b}\right) \times \sqrt{(1 + D_{x}^{2})} \ \left[\%\right]$
R, G	$\pm \left(E_{a} + E_{b}\right) \times \sqrt{(1 + Q_{x}^{2})} \left[\%\right]$
ΔD	
at $\left D_{x} \tan \left(\frac{E_{a} + E_{b}}{100} \right) \right < 1$	$\pm \frac{(1+D_x^2)\tan\left(\frac{E_a+E_b}{100}\right)}{1\mp D_x}$
Especially, at $D_x \le 0.1$	$\pm \frac{E_a + E_b}{100}$
Δ0	
at $\left Q_x \tan \left(\frac{E_a + E_b}{100} \right) \right < 1$	$\pm \frac{\left(1+Q_{x}^{2}\right)\tan\left(\frac{E_{a}+E_{b}}{100}\right)}{1\mp Q_{x} \tan\left(\frac{E_{a}+E_{b}}{100}\right)}$
Especially, at $\frac{10}{E_a + E_b} \ge 0_x \ge 10$	$\pm Q_x^2 \ \frac{E_a + E_b}{100}$

Measurement uncertainty

When OPEN/SHORT/LOAD/Low Loss capacitance calibration is performed (SPD):

Z, Y	$\pm \left(E_{a} + E_{b}\right) \left[\%\right]$
$\Delta heta$	$\pm \frac{E_{c}}{100}$ [rad]
L, C, X, B	$\pm \sqrt{\left(E_{a} + E_{b}\right)^{2} + \left(E_{c}D_{x}\right)^{2}} [\%]$
R, G	$\pm \sqrt{\left(E_{a} + E_{b}\right)^{2} + \left(E_{c} Q_{x}\right)^{2}} [\%]$
ΔD	
at $\left D_{x} \operatorname{tan} \left(\frac{E_{c}}{100} \right) \right < 1$	$\pm \frac{\left(1+D_{x}^{2}\right)\tan\left(\frac{E_{c}}{100}\right)}{1 \mp D_{x} \tan\left(\frac{E_{c}}{100}\right)}$
Especially, at $D_x \le 0.1$	$\pm \frac{E_{c}}{100}$
ΔQ	
at $\left \Omega_x \tan \left(\frac{E_c}{100} \right) \right < 1$	$\pm \frac{\left(1+Q_{x}^{2}\right)\tan\left(\frac{E_{c}}{100}\right)}{1\mp Q_{x} \tan\left(\frac{E_{c}}{100}\right)}$
Especially, at $\frac{10}{E_c} \ge 0_x \ge 10$	$\pm Q_x^2 \frac{E_c}{100}$

Definition of each parameter

Dx =	Measurement value of	fD						
Qx =	Measurement value of Q							
Ea =	Within 23 ± 5 °C from the calibration temperature. Measurement accuracy applies when the calibration is performed at 23 ± 5 °C. When							
	the calibration is performed beyond 23 ± 5 °C, the measurement accuracy decreases to half that described.							
	Measurement Time:	Oscillator level = 1 dBm	± 0.54 % at 1 MHz ≤ frequency ≤ 100 MHz					
	Mode 1		± 0.62 % at 100 MHz < frequency ≤ 500 MHz					
			± 0.92 % at 500 MHz < frequency ≤ 1 GHz					
			± 2.05 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 4.42 % at 1.8 GHz < frequency ≤ 3 GHz					
		–20 dBm ≤ Oscillator level < 1 dBm	± 0.66 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 0.74 % at 100 MHz < frequency ≤ 500 MHz					
			± 1.11 % at 500 MHz < frequency ≤ 1 GHz					
			± 2.36 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 4.81 % at 1.8 GHz < frequency ≤ 3 GHz					
		-33 dBm ≤ Oscillator level < –20 dBm	± 1.13 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 1.22 % at 100 MHz < frequency ≤ 500 MHz					
			± 1.84 % at 500 MHz < frequency ≤ 1 GHz					
			± 3.54 % at1 GHz < frequency ≤ 1.8 GHz					
			± 6.35 % at 1.8 GHz < frequency ≤ 3 GHz					
		Oscillator level < -33 dBm	± 2.08 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 2.26 % at 100 MHz < frequency ≤ 500 MHz					
			± 2.27 % at 500 MHz < frequency ≤ 1 GHz					
			± 4.34 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 7.60 % at 1.8 GHz < frequency ≤ 3 GHz					
	Mode 2	Oscillator level = 1 dBm	± 0.52 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 0.59 % at 100 MHz < frequency ≤ 500 MHz					
			± 0.89 % at 500 MHz < frequency ≤ 1 GHz					
			± 1.99 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 4.34 % at 1.8 GHz < frequency ≤ 3 GHz					
		–20 dBm ≤ Oscillator level < 1 dBm	± 0.58 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 0.66 % at 100 MHz < frequency ≤ 500 MHz					
			± 0.98 % at 500 MHz < frequency ≤ 1 GHz					
			± 2.14 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 4.54 % at 1.8 GHz < frequency ≤ 3 GHz					
		–33 dBm ≤ Oscillator level < –20 dBm	± 0.81 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 0.90 % at 100 MHz < frequency ≤ 500 MHz					
			± 1.35 % at 500 MHz < frequency ≤ 1 GHz					
			± 2.74 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 5.31 % at 1.8 GHz < frequency ≤ 3 GHz					
		Oscillator level < -33 dBm	± 1.30 % at 1 MHz ≤ frequency ≤ 100 MHz					
			± 1.44 % at 100 MHz < frequency ≤ 500 MHz					
			± 1.44 % at 500 MHz < frequency ≤ 1 GHz					
			± 2.92 % at 1 GHz < frequency ≤ 1.8 GHz					
			± 5.59 % at 1.8 GHz < frequency ≤ 3 GHz					
	!							

Definition of each parameter (Continued)

Ea =	Mode 3	Oscillator level = 1 dBm	± 0.51 % at 1 MHz ≤ frequency ≤ 100 MHz
La -			± 0.59 % at 100 MHz < frequency \leq 500 MHz
			± 0.87 % at 500 MHz < frequency ≤ 1 GHz
			\pm 1.97 % at 1 GHz < frequency \leq 1.8 GHz
			± 4.32 % at 1.8 GHz < frequency ≤ 3 GHz
		–20 dBm ≤ Oscillator level < 1 dBm	± 0.55 % at 1 MHz \leq frequency ≤ 100 MHz
			$\pm 0.63\%$ at 100 MHz < frequency ≤ 500 MHz
			\pm 0.94 % at 500 MHz < frequency \leq 1 GHz
			± 2.08 % at 1 GHz < frequency ≤ 1.8 GHz
			$\pm 4.46 \% \text{ at } 1.8 \text{ GHz} < \text{frequency} \le 3 \text{ GHz}$
		–33 dBm ≤ Oscillator level < –20 dBm	$\pm 0.65\%$ at 1 MHz \leq frequency ≤ 100 MHz
			± 0.80 % at 100 MHz < frequency ≤ 500 MHz
			± 1.20 % at 500 MHz < frequency ≤ 1 GHz
			± 2.50 % at 1 GHz < frequency ≤ 1.8 GHz
			± 5.00 % at 1.8GHz < frequency ≤ 3 GHz
		Oscillator level < -33 dBm	± 1.00 % at 1 MHz ≤ frequency ≤ 100 MHz
			± 1.20 % at 100 MHz < frequency ≤ 500 MHz
			± 1.20 % at 500 MHz < frequency ≤ 1 GHz
			± 2.50 % at 1 GHz < frequency ≤ 1.8 GHz
			± 5.00 % at 1.8 GHz < frequency ≤ 3 GHz
		1	
Eb =	$\pm \left(\frac{Zs}{ Zx } + Yo \right) \times$	/	(Zx : Measurement value of Z)
ED =	$\pm \left(\frac{Zs}{ Zx } + Yo \times \frac{1}{ Zx }\right)$ $\pm \left(0.06 + \frac{0.08}{100}\right)$	/	(Zx : Measurement value of Z) (F : Frequency [MHz])
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$	×F) [%]	(F : Frequency [MHz])
	$\pm \left(0.06 + \frac{0.08}{100} \right)$ Within 23 ± 5 °C from	/ ×F 0) [%] the calibration temperature. Measurement accurac	(F : Frequency [MHz])
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is performed	/ ×F 0) [%] the calibration temperature. Measurement accurace primed beyond 23 ± 5 °C, the measurement accurace	(F : Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When cy decreases to half that described. (F: Frequency [MHz])
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	/ ×F 0) [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8	(F : Frequency [MHz]) by applies when the calibration is performed at 23 ± 5 °C. When by decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is performed	/ ×F 0) [%] the calibration temperature. Measurement accurac prmed beyond 23 ± 5 °C, the measurement accurac Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8	(F: Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When cy decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	/ ×F 0 (%] the calibration temperature. Measurement accurace primed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average	(F : Frequency [MHz]) by applies when the calibration is performed at 23 ± 5 °C. When by decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8</pre>	(F : Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When cy decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8 -20 dBm ≤ Oscillator level < 1 dBm, Average</pre>	(F: Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When cy decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8</pre>	(F: Frequency [MHz]) (F: Frequency [MHz]) (y applies when the calibration is performed at 23 ± 5 °C. When y decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$ $\pm (37 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8 -33 dBm ≤ Oscillator level < -20 dBm, Average</pre>	(F : Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When cy decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace ormed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8 -33 dBm ≤ Oscillator level < -20 dBm, Average factor ≥ 8</pre>	(F: Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When y decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$ $\pm (37 + 0.5 \times F) [m\Omega]$ $\pm (36 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	<pre>/ ×F 0 [%] the calibration temperature. Measurement accurace prmed beyond 23 ± 5 °C, the measurement accurace Oscillator level = 1 dBm, Average factor ≥ 8 Oscillator level = 1 dBm, Average factor < 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8 -20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8 -33 dBm ≤ Oscillator level < -20 dBm, Average</pre>	(F: Frequency [MHz]) (F: Frequency [MHz]) (y applies when the calibration is performed at 23 ± 5 °C. When y decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$ $\pm (37 + 0.5 \times F) [m\Omega]$
Ec =	$\pm \left(0.06 + \frac{0.08}{100}\right)$ Within 23 ± 5 °C from the calibration is perform Measurement Time:	Y ×F) [%] the calibration temperature. Measurement accurace formed beyond 23 ± 5 °C, the measurement accurace or med beyond 23 ± 5 °C, the measurement accurace or med beyond 23 ± 5 °C, the measurement accurace of the description of the descri	(F: Frequency [MHz]) cy applies when the calibration is performed at 23 ± 5 °C. When y decreases to half that described. (F: Frequency [MHz]) $\pm (14 + 0.5 \times F) [m\Omega]$ $\pm (19 + 0.5 \times F) [m\Omega]$ $\pm (20 + 0.5 \times F) [m\Omega]$ $\pm (37 + 0.5 \times F) [m\Omega]$ $\pm (36 + 0.5 \times F) [m\Omega]$

Definition of each parameter (Continued)

Zs =	Mode 2	Oscillator level= 1 dBm, Average factor ≥ 8	± (13 + 0.5 × F) [mΩ]				
		Oscillator level= 1 dBm, Average factor < 8	± (15 + 0.5 × F) [mΩ]				
		–20 dBm ≤ Oscillator level < 1 dBm, Average	$\pm (16 + 0.5 \times F) [m\Omega]$				
		factor ≥ 8					
		–20 dBm ≤ Oscillator level < 1 dBm, Average	$\pm (24 + 0.5 \times F) [m\Omega]$				
		factor < 8					
		-33 dBm ≤ Oscillator level< -20 dBm, Average	±(24+0.5×F) [mΩ]				
		factor ≥ 8					
		-33 dBm ≤ Oscillator level < -20 dBm, Average	$\pm (64 + 0.5 \times F) [m\Omega]$				
		factor < 8					
		Oscillator level < –33 dBm	$\pm (133 + 0.5 \times F) [m\Omega]$				
	Mode 3	Oscillator level = 1 dBm, Average factor ≥ 8	$\pm (12 + 0.5 \times F) [m\Omega]$				
		Oscillator level = 1 dBm, Average factor < 8	$\pm (14 + 0.5 \times F) [m\Omega]$				
		-20 dBm ≤ Oscillator level < 1 dBm, Average factor ≥ 8	$\pm (15 + 0.5 \times F) [m\Omega]$				
		-20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8	± (20 + 0.5 × F) [mΩ]				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor ≥ 8	± (20 + 0.5 × F) [mΩ]				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor < 8	± (50 + 0.5 × F) [mΩ]				
		Oscillator level < -33 dBm	± (100 + 0.5 × F) [mΩ]				
Yo =	Within 22 + 5 °C from	in 23 ± 5 °C from the calibration temperature. Measurement accuracy applies when the calibration is performed at 23 ± 5 °C. When					
10 -	the calibration is performed beyond 23 ± 5 °C, the measurement accuracy decreases to half that described. (F: Frequency [MHz])						
	Measurement Time:	Oscillator level = 1 dBm, Average factor ≥ 8	$\pm (22 + 0.15 \times F) [\mu S]$				
	Mode 1	Oscillator level = 1 dBm, Average factor < 8	$\pm (28 + 0.15 \times F) [\mu S]$				
		$-20 \text{ dBm} \le \text{Oscillator level} < 1 \text{ dBm}$, Average	$\pm (30 + 0.15 \times F) [\mu S]$				
		factor ≥ 8					
		-20 dBm ≤ Oscillator level < 1 dBm, Average factor < 8	$\pm (53 + 0.15 \times F) [\mu S]$				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor ≥ 8	$\pm (52 + 0.15 \times F) [\mu S]$				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor < 8	± (110 + 0.15 × F) [μS]				
		Oscillator level < -33 dBm	± (247 + 0.15 × F) [μS]				
	Mode 2	Oscillator level = 1 dBm, Average factor ≥ 8	$\pm (20 + 0.15 \times F) [\mu S]$				
		Oscillator level = 1 dBm, Average factor < 8	$\pm (23 + 0.15 \times F) [\mu S]$				
		-20 dBm ≤ Oscillator level < 1 dBm, Average	$\pm (24 + 0.15 \times F) [\mu S]$				
		factor ≥ 8					
		–20 dBm ≤ Oscillator level < 1 dBm, Average	± (35 + 0.15 × F) [μS]				
		factor < 8	s - ver-a				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor ≥ 8	± (35 + 0.15 × F) [μS]				
		-33 dBm ≤ Oscillator level < -20 dBm, Average factor < 8	± (63 + 0.15 × F) [μS]				
		Oscillator level < -33 dBm	± (133 + 0.15 × F) [μS]				
		I Deciliator laval Z _33 dRm					

Definition of each parameter (Continued)

Yo =	Mode 3	Oscillator level = 1 dBm, Average factor ≥ 8	± (19 + 0.15 × F) [μS]
		Oscillator level = 1 dBm, Average factor < 8	± (22 + 0.15 × F) [μS]
		–20 dBm ≤ Oscillator level < 1 dBm, Average	± (22 + 0.15 × F) [μS]
		factor ≥ 8	
		–20 dBm ≤ Oscillator level < 1 dBm, Average	± (30 + 0.15 × F) [μS]
		factor < 8	
		–33 dBm ≤ Oscillator level < –20 dBm, Average	± (30 + 0.15 × F) [μS]
		factor ≥ 8	
		–33 dBm ≤ Oscillator level < –20 dBm, Average	± (50 + 0.15 × F) [μS]
		factor < 8	
		Oscillator level < -33 dBm	$\pm (100 + 0.15 \times F) [\mu S]$

Measurement error may exceed the specifications described above at 90 MHz due to the E4982A's spurious characteristics.

Examples of Calculated Impedance Measurement Accuracy



Figure 1. Measurement Time: Mode 3, Oscillator Level = 1 dBm, Averaging Factor < 8, Temperature Deviation ≤ 5 °C



Figure 3. Measurement Time: Mode 1, Oscillator Level = 1 dBm, Averaging Factor < 8, Temperature Deviation ≤ 5 °C



Figure 5. Measurement Time: Mode 2, Oscillator Level = 1 dBm, Averaging Factor \ge 8, Temperature Deviation \le 5 °C



Figure 2. Measurement Time: Mode 2, Oscillator Level = 1 dBm, Averaging Factor < 8, Temperature Deviation \leq 5 °C



Figure 4. Measurement Time: Mode 3, Oscillator Level = 1 dBm, Averaging Factor ≥ 8, Temperature Deviation ≤ 5 °C



Figure 6. Measurement Time: Mode 1, Oscillator Level = 1 dBm, Averaging Factor \ge 8, Temperature Deviation \le 5 °C

Timing Chart and Measurement Time (SPD)



Figure 7. Timing chart of handler interface signal.

Cycle Time

		Test condition		Test condition Timing												
				Mode 1 (1 MHz) Mode 1 (100 MHz)			MHz)	Mode 2				Mode 3				
		Screen setting	Rdc meas.	Comparator	Min.	Median	Max.	Min.	Median	Max.	Min.	Median	Max.	Min.	Median	Мах.
T1	Trigger pulse width	_	Off	Off	2 µs	-	-	2 µs	-	-	2 µs	-	-	2 µs	-	_
T2	Trigger response time of Ready_for_Trig	-	Off	Off		-	< 50 μs		_	< 50 μs		—	< 50 μs		—	< 50 μs
Т3	Trigger response time (INDEX, EOM)	-	Off	Off		-	< 50 μs		-	< 50 μs		_	< 50 μs		_	< 50 μs
T4	Measurement time (INDEX)	1 point	Off	Off	-	1.6	1.6		0.9	0.9		2.1	2.1		3.7	3.7
		meas				ms	ms		ms	ms		ms	ms		ms	ms
		(Preset)	On	Off	-	4.5	4.5		3.8	3.8		5.0	5.0		6.6	6.6
						ms	ms		ms	ms		ms	ms		ms	ms
T4	Measurement data	1 point	Off	Off	-	1.6	1.8		0.9	1.1		2.1	2.3		3.7	4.0
+	calculation time (EOM)	meas				ms	ms		ms	ms		ms	ms		ms	ms
T5		(Preset)	Off	On	-	1.7	1.9	-	1.0	1.2	-	2.2	2.7	-	3.8	4.1
						ms	ms		ms	ms		ms	ms		ms	ms
T4	Ready_for_Trig setting time	1 point	Off	Off	-	1.8	2.2	-	1.1	1.4	-	2.3	2.8	-	3.9	4.4
+		meas.				ms	ms		ms	ms		ms	ms		ms	ms
T5		Ls-Q	Off	On	-	1.9	2.3	-	1.2	1.9	-	2.4	3.3	-	4.0	4.5
+		meas.				ms	ms		ms	ms		ms	ms		ms	ms
T6			On	Off	-	5.1	5.6	-	4.4	4.9	-	5.6	6.1	-	7.2	7.7
						ms	ms		ms	ms		ms	ms		ms	ms
			On	On	-	5.2	5.7	-	4.5	4.9	-	5.7	6.3	-	7.2	7.8
						ms	ms		ms	ms		ms	ms		ms	ms
Τ7	Trigger wait time	_	-	-	0	-	_	0	_	_	0	—	-	0	-	-

Condition: Display Off or : DISP : UPD OFF, Trigger delay=0, Point delay=0 E4982A OS: Windows 7 (Serial Prefix: MY523)

Test Condition for Measurement Time

The measurement time of E4982A is scattered to some extent by an overhead of the internal operation system and other conditions, so it is difficult to define the specification of handler interface timing. Thus, for your reference, we provide "SPD" data on it in table by defining the following test condition.

Median: Median value of running one minute of measurement data Max.: Maximum value of running one minute of measurement data

NOTE

- The instrument's operating system sometimes suffers interruptions during measurement, and we sometimes observe an
 extremely large overhead in handler interface timings. The table excludes such special cases, thus you can sometimes see timing
 over the maximum value data shown in the table. If you make a handshake using the READY_FOR_TRIGGER signal of the handler
 interface, your test system can continue to work correctly regardless of such an irregular measurement time drift.
- 2. If your system communicates with external devices, you will see longer timing results than those on the table.
- 3. In the case of using a bus trigger in the GPIB/LAN/USB system instead of the handler interface, you should measure the test cycle time for yourself, because the system performance depends heavily on the system parameters. Of course, you will see much longer test cycle times from your system software overhead.



Figure 8. Measurement time T4 for single point measurement.



Figure 9. Measurement time T4 for list measurement.

Data Transfer Time (Typical)

Mode 3

Data transfer format	Number of measurement	Required time for FETCh? command (ms)						
	points	GPIB	USB	LAN (Socket)				
	1	0.4	0.4	0.6				
ASCII	2	0.7	0.4	0.6				
	3	1.0	0.4	0.7				
	1	0.5	1.1	0.6				
Binary	2	0.5	1.1	0.5				
	3	0.6	1.1	0.6				

Host computer	DELL PRECISION 390 Intel Core2Duo 6300 1.86 GHz/RAM: 2 GB			
GPIB I/F	Keysight Technologies, Inc. PCI GPIB E2078A/82350A			
IO Lib	Keysight IO Libraries Suite 16.1.14931.0			
E4982A setting				
Frequency	100 MHz			
OSC level	0 dBm			
Average	1			
Display	Off			
List measurement				
Measurement parameter	Ls-Q (Parameters No.3 and 4: Off)			
Measurement signal level monitor	Off			
Comparator	Off			
Rdc measurement	Off			

Error correction function

Available calibration and compensation

ritaliable ballbration and bomponet	
OPEN/SHORT/LOAD calibration	Connect OPEN, SHORT, and LOAD standards to the desired reference plane and measure each kind of
	calibration data. The reference plane is called calibration reference plane.
Low-Loss capacitor calibration	Connect the dedicated standard (Low-Loss capacitor) to the calibration reference plane and measure the
	calibration data.
Port extension compensation	When a device is connected to the terminal that is extended from the calibration reference plane, set the
(Fixture selection)	electrical length between the calibration plane and the device contact. Select a model number of the registered
	test fixtures in the E4982A's softkey menu or enter the electrical length for user's test fixture.
OPEN/SHORT compensation	When a device is connected to the terminal that is extended from the calibration reference plane, make OPEN
	and/or SHORT states at the device contact and measure each kind of compensation data.
Calibration/compensation data me	asurement point
Data measurement points	Same as measurement points which are set in the measurement point setup display.
	(Changing the frequency, oscillator level, or measurement time settings after the calibration or compensation
	makes the calibration and compensation data invalid.)

DC resistance (Rdc) measurement

Measurement range	0.1 Ω to 100 Ω
Measurement resolution	1 mΩ
Test signal level	1 mA (maximum)
Error correction	OPEN/SHORT/LOAD Calibration, OPEN/SHORT Compensation. (Changing the frequency or oscillator level settings after the calibration or compensation makes the calibration and compensation data invalid.)
Measurement uncertainty (SPD)	$\pm \left[1 + \left(\frac{0.05}{\text{Rdut}} + \frac{\text{Rdut}}{10000}\right) \times 100\right] \left[\%\right] \text{ Rdut : DC resistance measurement value } \left[\Omega\right]$
	(At averaging factor=128, within ± 5 °C from the calibration temperature. Measurement accuracy applies when the calibration is performed at 23 °C ± 5 °C. When the calibration is performed beyond 23 °C ± 5 °C, the measurement accuracy decreases to half that described.)

Trigger mode	Internal, External (external trigger input connector or handler interface), Bus (GPIB, USB or LAN), Manual (front
	key)

Measurement time

Time Mode 1 (Short), Mode 2 (Mid), Mode 3 (Long)
--

Averaging function

Setting range	1 to 100 (integer)	

List measurement function

Number of measurement points	201 points for each table (maximum)
Number of tables	8 tables

Test signal level monitor function

Uncertainty of monitor value (SPD)

$$\pm \left[30 + \left(10^{\frac{A}{20}} - 1 \right) \times 100 + B \right] [\%]$$

A: Uncertainty of oscillator level [dB], B: Uncertainty of impedance measurement [%]

Front panel

Ports	Type N (3 ea.) connected to test head	
Display	Type/size	10.4 inch TFT color LCD
	Resolution	XGA (1024 × 768) ¹
USB	Universal serial bus jack, Type A confi	guration; female; provides connection to mouse, key board, printer or USB
	stick memory.	

Measurement terminal (at test head)

Connector type	3.5-mm (female) connector (Can be converted to 7-mm connector using the 3.5 mm to 7 mm adapter)

Rear panel

External reference signal input conne	ctor
Frequency	10 MHz ± 10 ppm (Typ.)
Level	0 dBm ± 3 dB (Typ.)
Input impedance	50Ω (nominal)
Connector type	BNC (female)
Internal reference signal output conne	ector
Frequency	10 MHz ± 10 ppm (Typ.)
Uncertainty of frequency	Same as frequency uncertainty described in "Source Characteristics".
Level	0 dBm \pm 3 dB into 50 Ω (Typ.)
Output impedance	50 Ω (nominal)
Connector type	BNC (female)
External trigger signal input connecto	r
Level	LOW threshold voltage: 0.5 V
	HIGH threshold voltage: 2.1 V
	Input level range: 0 to +5 V
Pulse width (Tp)	\ge 2 µsec (SPD). See the following figure for definition of Tp
Polarity	Positive or negative (Selective)
Connector type	BNC (female)

1. Valid pixels are 99.99% and more. Below 0.01% of fixed points of black, blue, green or red are not regarded as failure.



Figure 10. Definition of pulse width (Tp).

Interface

GPIB	24-pin D-Sub (Type D-24), female; compatible with IEEE-488.
	IEEE-488 interface specification is designed to be used in environment where electrical noise is relatively low.
	LAN or USBTMC interface is recommended to use at the higher electrical noise environment.
USB host port	Universal serial bus jack, Type A configuration; female; provides connection to mouse, key board, printer or USB
	stick memory.
USB (USBTMC) interface port	Universal serial bus jack, Type B configuration (4 contacts inline); female; provides connection to an external PC;
	compatible with USBTMC-USB488 and USB 2.0.LA
	USB Test and Measurement Class (TMC) interface that communicates over USB, complying with the IEEE 488.1
	and IEEE 488.2 standards.
LAN	10/100/1000 Base T Ethernet, 8-pin configuration; auto selects between the two data rates
Video output	15-pin mini D-Sub; female; drives VGA compatible monitors

Handler interface

36-pin centronics, female
Negative logic, opto-isolated, open collector output
BIN sort result (BIN 1 to BIN 13, OUT_OF_GOOD_BINS)
DC resistance pass/fail (DCR_OUT_OF_RANGE)
Overload (OVLD)
Alarm (ALARM)
End of analog measurement (INDEX)
End of measurement (EOM)
Ready for trigger (READY_FOR_TRIG)
Eternal trigger (EXT_TRIG)
Key lock (KEY_LOCK)
See the following figure. Refer to Help for the definition of each pin.



Figure 11. Pin assignment.

Line power

Frequency	47 to 63 Hz
Voltage	90 to 264 VAC (Vpeak > 120 V)
VA max	300 VA max.

EMC, safety, environment and compliance

FMC	
EMC ESM 1-A	European Council Directive 2004/108/EC IEC 61326-1:2012 EN 61326-1:2013 CISPR 11:2009 +A1:2010 EN 55011: 2009 +A1:2010 Group 1, Class A IEC 61000-4-2:2008 EN 61000-4-2:2009 4 kV CD / 8 kV AD IEC 61000-4-3:2006 +A1:2007 +A2:2010 EN 61000-4-3:2006 +A1:2008 +A2:2010 3 V/m, 80-1000 MHz, 1.4 - 2.0 GHz / 1V/m, 2.0 to 2.7 GHz, 80% AM IEC 61000-4-4:2004 +A1:2010 EN 61000-4-4:2004 +A1:2010 1 kV power lines / 0.5 kV signal lines IEC 61000-4-5:2006 EN 61000-4-5:2006 0.5 kV line-line / 1 kV line-ground IEC 61000-4-6:2008 EN 61000-4-6:2009 3 V, 0.15-80 MHz, 80% AM IEC 61000-4-8:2010 30A/m, 50/60Hz IEC 61000-4-11:2004 EN 61000-4-11:2004
ICES/NMB-001	 0.5-300 cycle, 0% / 70% NOTE-1: When tested at 3 V/m according to EN61000-4-3, the measurement accuracy will be within specifications over the full immunity test frequency range except when the analyzer frequency is identical to the transmitted interference signal test frequency. NOTE-2: When tested at 3 V according to EN61000-4-6, the measurement accuracy will be within specifications over the full immunity test frequency range except when the analyzer frequency is identical to the transmitted interference signal test frequency. ICES-001:2006 Group 1, Class A
	AS/NZS CISPR11:2004
\bigotimes	Group 1, Class A
MSIP-REM-Kst- WNMODSF36	KN11, KN61000-6-1 and KN61000-6-2 Group 1, Class A

EMC, safety, environment and compliance (Continued)

Safety	
((European Council Directive 2006/95/EC
	IEC 61010-1:2001 / EN 61010-1:2001
ISM 1-A	Measurement Category I
	Pollution Degree 2
	Indoor Use
	NOTE-1:
	When tested at 3 V/m according to EN61000-4-3, the measurement accuracy will be within specifications
	over the full immunity test frequency range except when the analyzer frequency is identical to the transmitted
	interference signal test frequency.
	NOTE-2:
	When tested at 3 V according to EN61000-4-6, the measurement accuracy will be within specifications over
	the full immunity test frequency range except when the analyzer frequency is identical to the transmitted
	interference signal test frequency.
	CAN/CSA C22.2 No. 61010-1-04
(SP	Measurement Category I
	Pollution Degree 2
LR95111C	Indoor Use
Environment	
	This product complies with the WEEE Directive (2002/96/EC) marking requirements. The affixed label indicates
	that you must not discard this electrical/electronic product in domestic household waste.
	Product Category: With reference to the equipment types in the WEEE Directive Annex I, this product is classed
<u>∕</u> _ð	as a "Monitoring and Control instrumentation" product. Do not dispose in domestic household waste.
	To return unwanted products, contact your local Keysight Office.
Compliance	
	Class C

Environmental Specifications and Dimensions

Operating environment		
Temperature	+5 °C to +40 °C	
Error-corrected temperature range	23 °C (± 5 °C) with < 5 °C deviation from calibration temperature	
Humidity	20% to 80% at wet bulb temperature < +29 °C (non-condensation)	
Altitude	0 to 2,000 m (0 to 6,561 feet)	
Vibration	0.21 Grms maximum, 5 Hz to 500 Hz	
Non-operating environment		
Temperature	–10 °C to +60 °C	
Humidity	20% to 90% at wet bulb temperature < 40 °C (non-condensation)	
Altitude	0 to 4,572 m (0 to 15,000 feet)	
Vibration	2.1 Grms maximum, 5 Hz to 500 Hz	
Dimensions, weight		
Weight	Main unit: 13 kg, test head: 250 g with plate	



Figure 12. Front view.



Figure 13. Rear view.



Figure 14. Side view.









Figure 15. Test head.

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